

Description

The VSM26N18 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

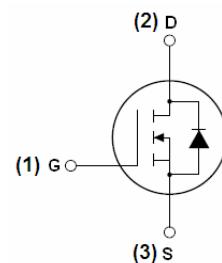
- $V_{DS} = 185V, I_D = 26A$
- $R_{DS(ON)} < 60m\Omega @ V_{GS}=10V$ (Typ:50m Ω)
- High density cell design for ultra low $R_{DS(on)}$
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



TO-252



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM26N18-T2	VSM26N18	TO-252	-	-	-

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	185	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	26	A
Drain Current-Continuous($T_c=100^\circ C$)	$I_D(100^\circ C)$	18.4	A
Pulsed Drain Current	I_{DM}	100	A
Maximum Power Dissipation	P_D	150	W
Single pulse avalanche energy ^(Note 5)	E_{AS}	25	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 175	°C

Thermal Characteristic

Thermal Resistance,Junction-to-Case ^(Note 2)	$R_{\theta JC}$	1	°C/W
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Electrical Characteristics ($T_c=25^\circ C$ unless otherwise noted)

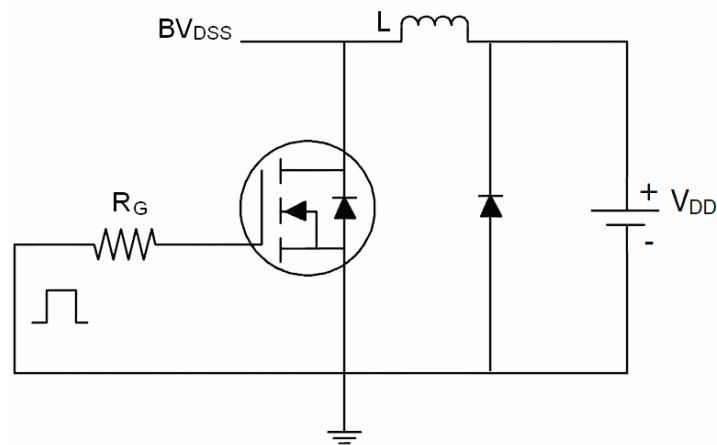
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	185	-	-	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=185V, V_{GS}=0V$	-	-	1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
On Characteristics ^(Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0	3.0	4.0	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=15A$	-	50	60	$m\Omega$
Forward Transconductance	g_{FS}	$V_{DS}=5V, I_D=10A$	17	-	-	S
Dynamic Characteristics ^(Note 4)						
Input Capacitance	C_{iss}	$V_{DS}=50V, V_{GS}=0V,$ $F=1.0MHz$		4118		PF
Output Capacitance	C_{oss}			120		PF
Reverse Transfer Capacitance	C_{rss}			91		PF
Switching Characteristics ^(Note 4)						
Turn-on Delay Time	$t_{d(on)}$	$V_{DS}=100V, I_D=15A$ $V_{GS}=10V, R_{GEN}=2.5\Omega$	-	10	-	nS
Turn-on Rise Time	t_r		-	18	-	nS
Turn-Off Delay Time	$t_{d(off)}$		-	22	-	nS
Turn-Off Fall Time	t_f		-	5	-	nS
Total Gate Charge	Q_g	$V_{DS}=100V, I_D=15A,$ $V_{GS}=10V$		90.7		nC
Gate-Source Charge	Q_{gs}			17.4		nC
Gate-Drain Charge	Q_{gd}			30.4		nC
Drain-Source Diode Characteristics						
Diode Forward Voltage ^(Note 3)	V_{SD}	$V_{GS}=0V, I_S=15A$	-	-	1.2	V
Diode Forward Current ^(Note 2)	I_S	-	-	-	26	A
Reverse Recovery Time	t_{rr}	$T_J = 25^\circ C, I_F = 15A$ $di/dt = 100A/\mu s$ ^(Note 3)	-	90	-	nS
Reverse Recovery Charge	Q_{rr}		-	300	-	nC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

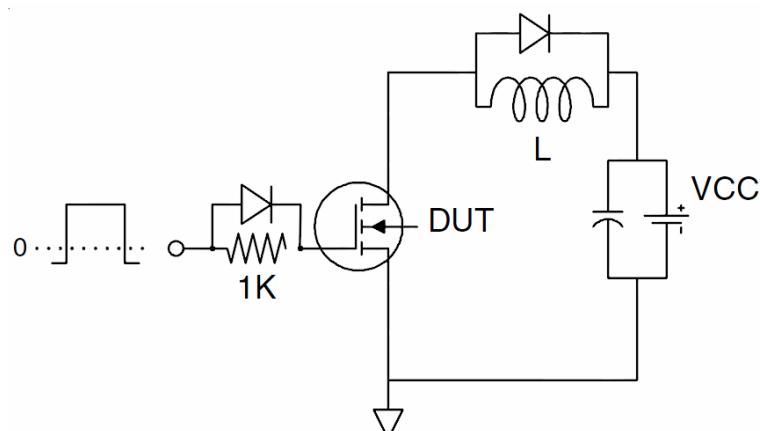
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS condition: $T_j=25^\circ C, V_{DD}=100V, V_G=10V, L=0.5mH, R_g=25\Omega$

Test Circuit

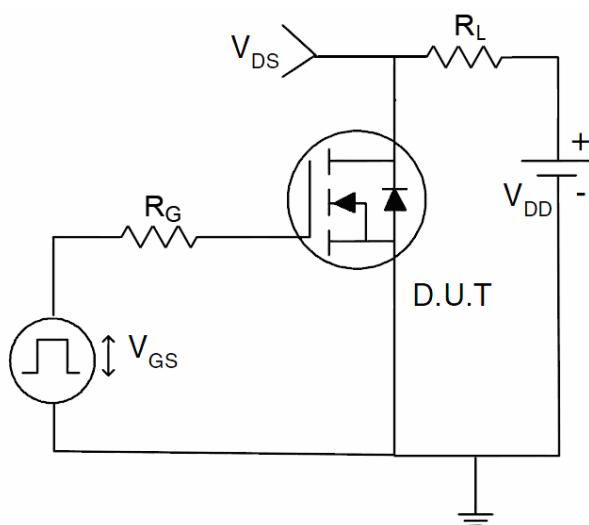
1) E_{AS} test Circuits



2) Gate charge test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

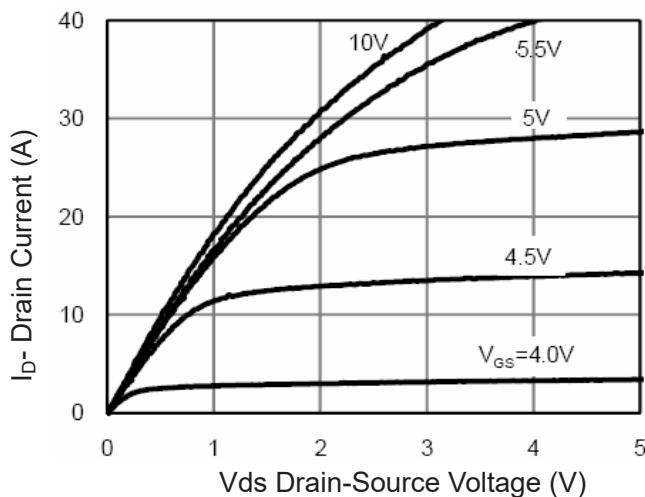


Figure 1 Output Characteristics

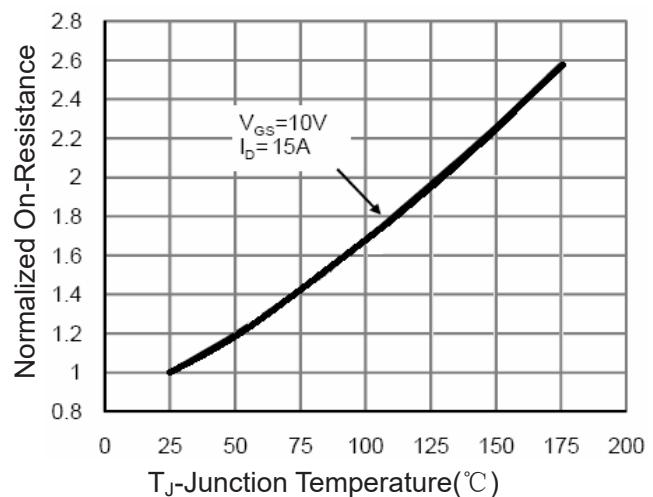


Figure 4 Rdson-JunctionTemperature

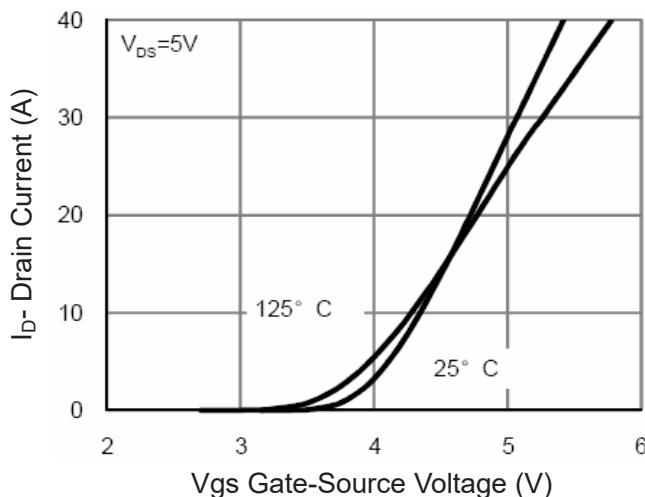


Figure 2 Transfer Characteristics

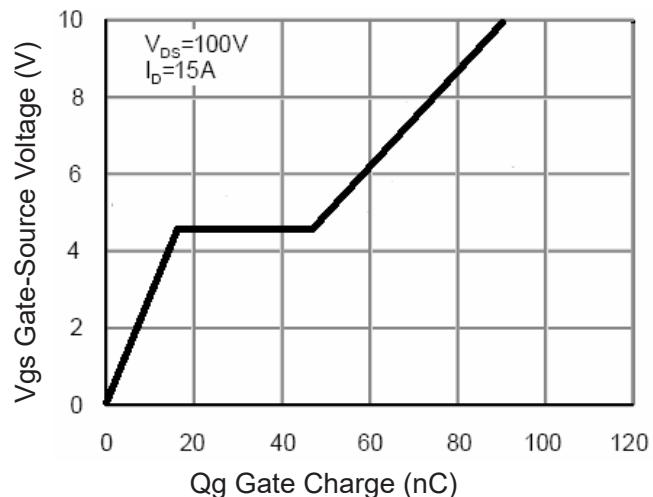


Figure 5 Gate Charge

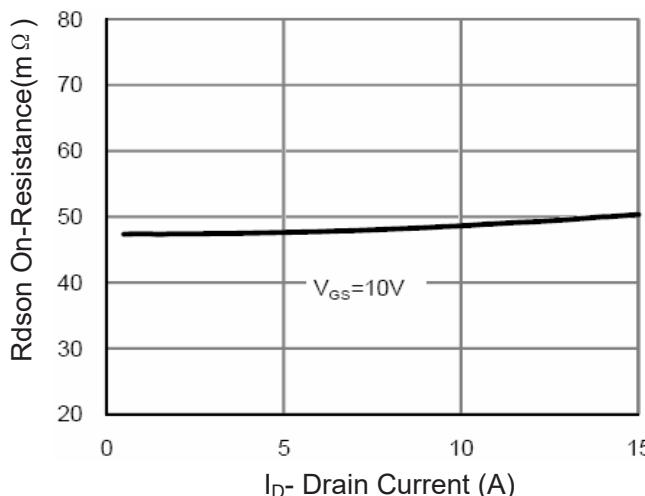


Figure 3 Rdson- Drain Current

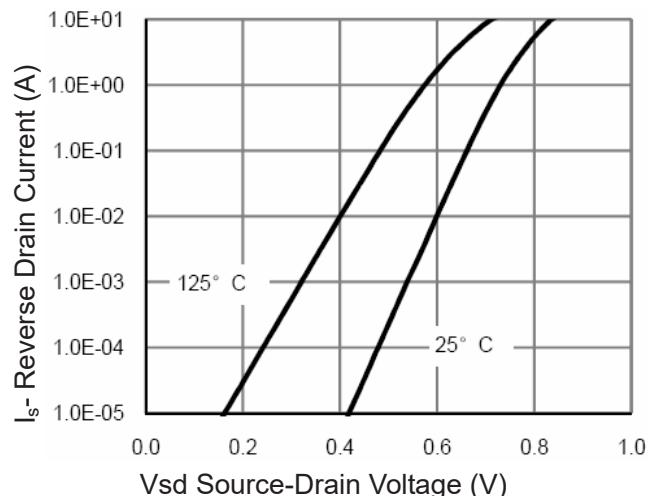
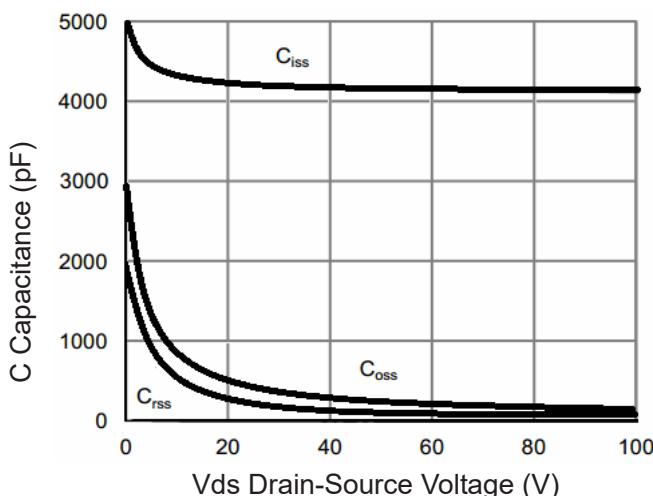
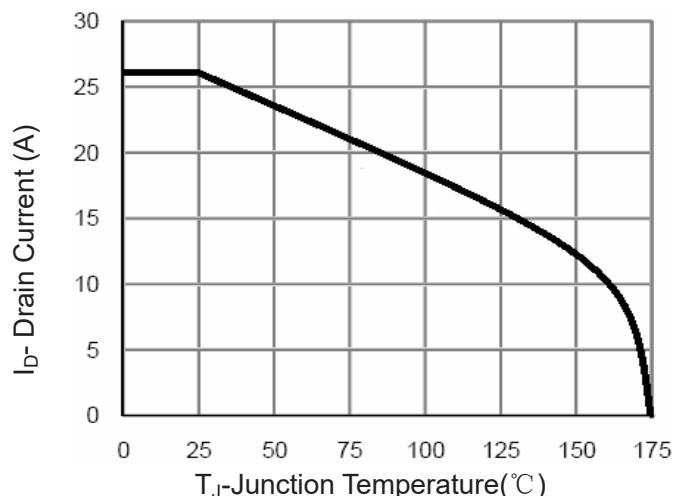
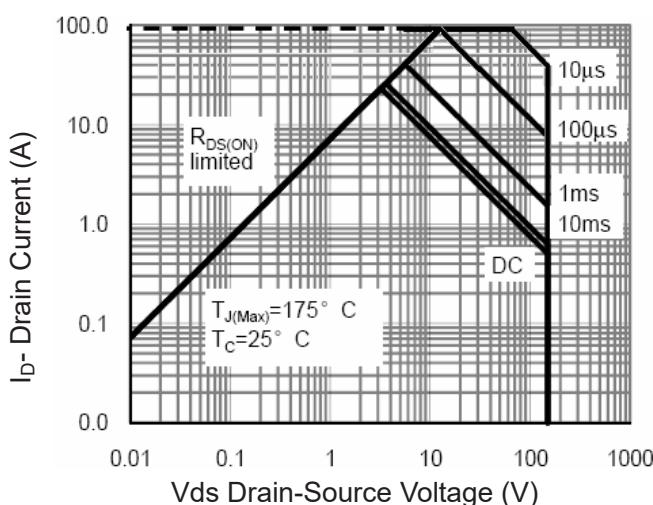
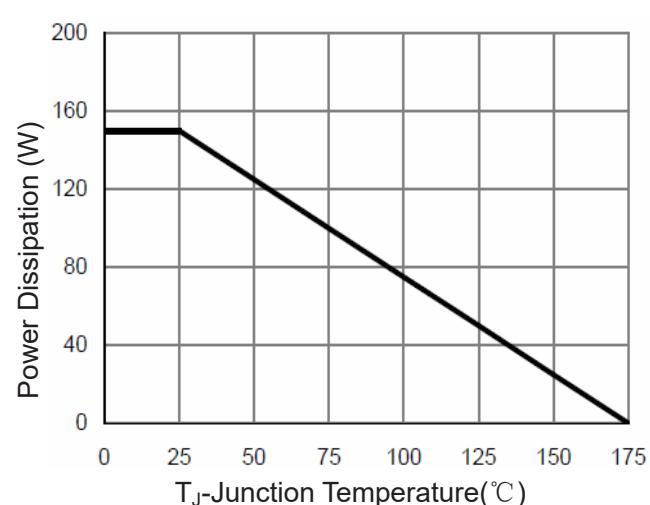
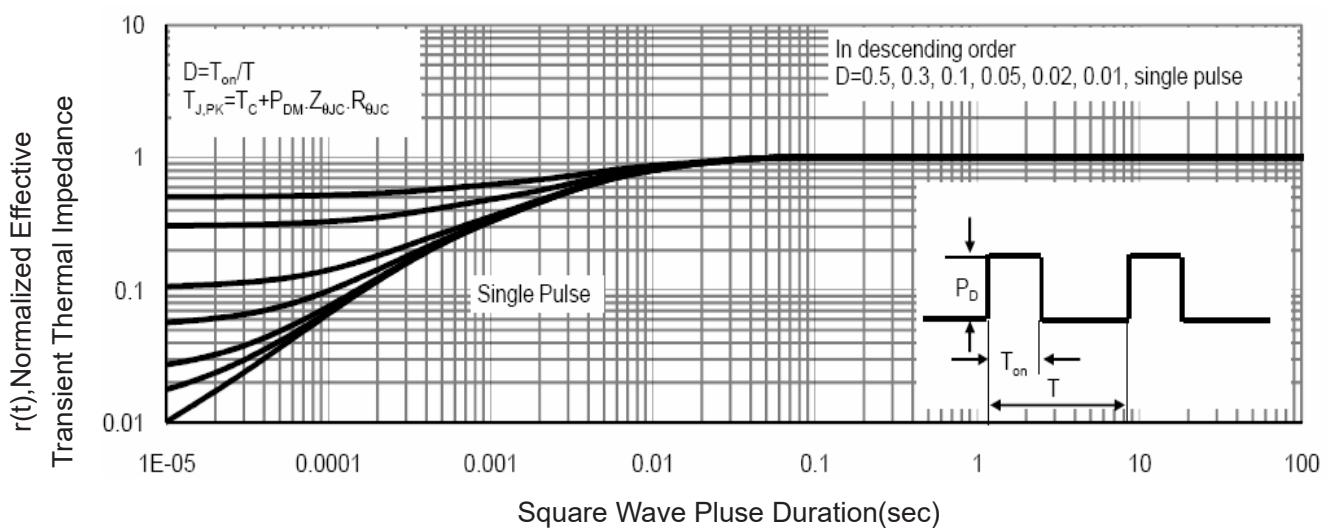


Figure 6 Source- Drain Diode Forward


Figure 7 Capacitance vs Vds

Figure 9 Current De-rating

Figure 8 Safe Operation Area

Figure 10 Power De-rating

Figure 11 Normalized Maximum Transient Thermal Impedance